

The 37th RD50 Workshop (Zagreb -- online Workshop)

Wednesday, 18 November 2020

Defect Characterization: Defect Characterization (09:20 - 13:30)

-Conveners: Aneliya Karadzhinova-Ferrer; Ioana Pintilie

time	[id] title	presenter
09:20	[17] Structural, compositional and defect studies on hadron irradiated B-doped silicon diodes	PINTILIE, Ioana
09:40	[24] Defect investigations of electron irradiated p-type Si sensors	HIMMERLICH, Anja
10:00	[3] The boron-oxygen (BiOi) defect complex induced by irradiation with 23 GeV protons in p-type epitaxial silicon diodes	Mr LIAO, Chuan
10:20	[23] An increase of the quantum yield in highly irradiated Si.	VAITKUS, Juozas
10:40	Coffee Break	
10:50	[25] Alpha irradiation induced stability studies in single crystal diamond radiation detectors	Dr NARASIMHA MURTY, N V L
11:10	[28] Electron, neutron and proton irradiation effects on four-quadrant SiC radiation detectors	Dr RAFÍ, Joan Marc
11:30	[38] Discussion: Defect and Material Characterization	PINTILIE, Ioana
12:00	Lunch Break	